

Notice of References Cited

Application/Control No.

09/542,611

Applicant(s)/Patent Under
Reexamination
SWIFT ET AL.

Examiner

Jean W. Désir

Art Unit

2614

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,545,719 B1	04-2003	Topper, Robert J.	348/448
	B	US-5,682,205	10-1997	Sezan et al.	348/452
	C	US-5,579,054 A	11-1996	Sezan et al.	348/452
	D	US-6,628,711 B1	09-2003	Mathew et al.	375/240.12
	E	US-5,510,834 A	04-1996	Weiss et al.	348/97
	F	US-5,016,102	05-1991	Avis, Richard J. A.	348/452
	G	US-5,844,613 A	12-1998	Chaddha, Navin	375/240.12
	H	US-5,430,480 A	07-1995	Allen et al.	348/208.4
	I	US-6,580,812 B1	06-2003	Harrington, Steven J.	382/107
	J	US-6,269,484 B1	07-2001	Simsic et al.	725/151
	K	US-6,252,975 B1	06-2001	Bozdagi et al.	382/107
	L	US-6,205,178 B1	03-2001	Suzuki et al.	375/240.15
	M	US-6,115,502 A	09-2000	De Haan et al.	382/260

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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